

Specification	AXIOM75-25	Rev.: 2	Date: 2014-07-09
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Oscillator type: Low Phase Noise OCXO with Sine Wave Output

Parameter	min.	typ.	max.	Unit	Condition
Nominal frequency	130.000			MHz	
Frequency stability					
Initial tolerance @ +25°C			±500	ppb	@ V _{REF} /2
vs. operating temperature range			±50	ppb	
operating temperature range	-10		+60	°C	
vs. supply voltage variation			±5	ppb	V _S ±5%
vs. load change			±5	ppb	R _L ±5%
Long term (aging) per day		±1	±2	ppb	after 30 days operation
Long term (aging) 1 st year			±100	ppb	after 30 days operation
Frequency adjustment range					
Electronic Frequency Control (EFC)	±0.8	±1		ppm	
EFC voltage V _C	0		VREF	V	
EFC slope (Δf / ΔV _C)	Positive				
EFC input impedance	100			kΩ	
RF output					
Signal waveform	Sine wave				R _L = 50 Ω
Output level	+7			dBm	
Harmonics			-30	dBc	
Spurious			-90	dBc	
Warm-up time			5	min	Δf _{final} /f ₀ < ±0.1 ppm
Phase noise		-85 -120 -150 -160 -160		dBc/Hz dBc/Hz dBc/Hz dBc/Hz dBc/Hz	@ 10 Hz @ 100 Hz @ 1kHz @ 10 kHz @ 100 kHz
Reference voltage VREF output		8.0		V	
Supply voltage V_S	9.5	10.0	10.5	V	
Current consumption (steady state)			100	mA	@ +25°C
Current consumption (warm-up)			250	mA	
Operable temperature range	-20		+70	°C	
Storage temperature range	-40		+85	°C	
Enclosure (see drawing) (LxWxH) (Note 6)	25.8x25.8x12.7 max.			mm	IEC 60679-3 CO 43
Weight			10	g	
Handling and Testing	In accordance with AXAN-011				www.axtal.com
Processing	In accordance with AXAN-012				www.axtal.com

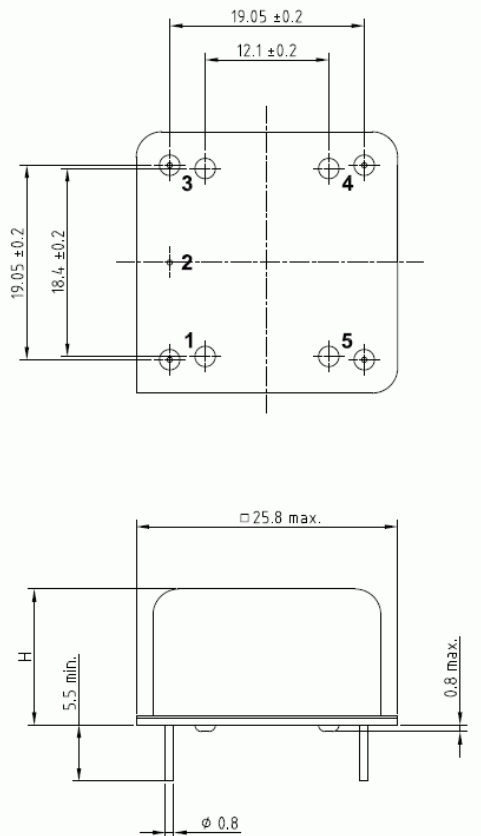
Notes:

1. Terminology and test conditions are according to IEC standard IEC60679-1, unless otherwise stated

Ordering Code:

Model (Specification)	Revision	Frequency [MHz]
AXIOM75-25	Rev.2	130.000

Enclosure drawing



Pin connections

Pin #	Symbol	Function
1	RF OUT	RF Output
2	GND	Ground
3	V_C	Control Voltage (EFC)
4	VREF	Reference Voltage
5	V_S	Supply Voltage

Environmental conditions

Test	IEC 60068 Part ...	IEC 60679-1 clause ...	Test conditions
Sealing tests (if applicable)	2-17	4.6.2	Gross leak: Test Qc, Fine leak: Test Qk
Solderability Resistance to soldering heat	2-20 2-58	4.6.3	Test Ta (235 ± 5)°C Method 1 Test Tb Method 1A, 5s
Shock*	2-27	4.6.8	Test Ea, 3 x per axes 100g, 6 ms half-sine pulse
Vibration, sinusoidal*	2-6	4.6.7	Test Fc, 30 min per axes, 10 Hz - 55 Hz 0,75mm; 55 Hz - 2 kHz, 10g
Endurance tests - ageing - extended aging		4.7.1 4.7.2	30 days @ 85°C, OCXO @25°C 1000h, 2000h, 8000h @85°C

Revision History

Rev.	Drawing	Date [dd.mm.yyyy]	Remarks	Author	Checked
1	D0	21.07.2011	First issue	BN	BN
2	D0	15.08.2011	Phase noise changed	BN	BN
2	D1	09.07.2014	Editorial changes	HH	HH